



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Susumu NODA et al.

Application No.: 10/584,942 ✓

Filed: July 5, 2006

Docket No.: 126785

For: PHOTONIC CRYSTAL HAVING HETERO STRUCTURE AND OPTICAL DEVICE
USING THE PHOTONIC CRYSTAL

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

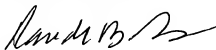
Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of one or more non-English language reference is discussed in the present specification. See References 21, 23 and 30.
- ☒ 3. One or more reference cited herein was cited in the International Search Report. A copy of the International Search Report is attached for the Examiner's information. See References 1 - 8, 11 - 20, 28 and 29.
- ☒ 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 5. An English language Abstract of one or more non-English language reference is attached hereto. See References 11, 14, 16 - 21, 23 - 25 and 27.

- ☒ 6. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office (<http://www.jpo.go.jp>), and is attached, but has not been reviewed for accuracy. See References 11, 14 and 16 - 27.
- ☒ 7. References 1 - 3, 12 and 13 correspond to reference 11. References 4 and 15 correspond to reference 14. References 5 and 6 correspond to reference 16. References 7 and 8 correspond to reference 17. References 9 and 10 correspond to reference 19.
- ☒ 8. References 23, 25 and 27 are the unexamined publication of references 22, 24 and 26, respectively.

Respectfully submitted,



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DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461
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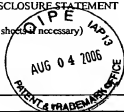


Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 126785		APPLICATION NO. 10/584,942	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)							
				APPLICANTS Susumu NODA et al.			
				FILING DATE July 5, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
	1	6,130,969	10/10/2000	VILLENEUVE et al.			
	2	2002/0118923 A1	8/29/2002	WANG et al.			
	3	6,512,866 B1	1/28/2003	FAN et al.			
	4	6,310,991 B1	10/30/2001	KOOPS et al.			
	5	2004/0017960 A1	1/29/2004	PLATZMAN et al.			
	6	2004/0184715 A1	9/23/2004	PLATZMAN et al.			
	7	5,253,319	10/12/1993	BHAGAVATULA			
	8	5,612,171	3/18/1997	BHAGAVATULA			
	9	6,738,551 B2	5/18/2004	NODA et al.			
	10	2002/0009277 A1	1/24/2002	NODA et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	11	JP A 2001-508887	7/3/2001	Japan	X	X	
	12	WO 03/077023 A1	9/18/2003	WIPO			
	13	WO 98/57207	12/17/1998	WIPO			
	14	JP A 2002-510400	4/2/2002	Japan	X	X	
	15	WO 98/53350	11/26/1998	WIPO			
	16	JP A 2002-268105	9/18/2002	Japan	X	X	
	17	JP A 6-88915	3/29/1994	Japan	X	X	
	18	JP A 2004-233941	8/19/2004	Japan	X	X	
	19	JP A 2004-334190	11/25/2004	Japan	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /R.P./							
EXAMINER /Rhonda Peace/					DATE CONSIDERED 02/16/2010		

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	20	JP A 2004-212416	7/29/2004	Japan	X	X
	21	JP A 2001-272555	10/5/2001	Japan	X	X
	22	JP B2 3459827	8/8/2003	Japan		X
	23	JP A 2003-279764	10/2/2003	Japan	X	X
	24	JP B2 3334381	8/2/2002	Japan	X	X
	25	JP A 8-160259	6/21/1996	Japan	X	X
	26	JP B2 3417373	4/11/2003	Japan		X
	27	JP A 2001-215350	8/10/2001	Japan	X	X

OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)
	28	Takashi Asano et al., "Optical Add/Drop Filter Using 2D Photonic Crystal Slab -Interference between single defects-," 29p-L-7, p. 1039, 2002.
	29	B.S.Song et al., "Optical Add/Drop Filter Using an In-plane Hetero Photonic Crystal," 25p-YA-17, p. 916, 2002.
	30	Y. Tanaka et al., "Effects of TM-like Slab Mode on Line-Defect Waveguide in 2D Photonic Crystal Slab," 28a-YN-9, p. 1129 2003.
	31	Alongkam Chutinan et al. "Waveguides and waveguide bends in two-dimensional photonic crystal slabs," Physical Review B, Vol. 62, No. 7, pp. 4488-4492, 2000.

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